

FIGURE 1

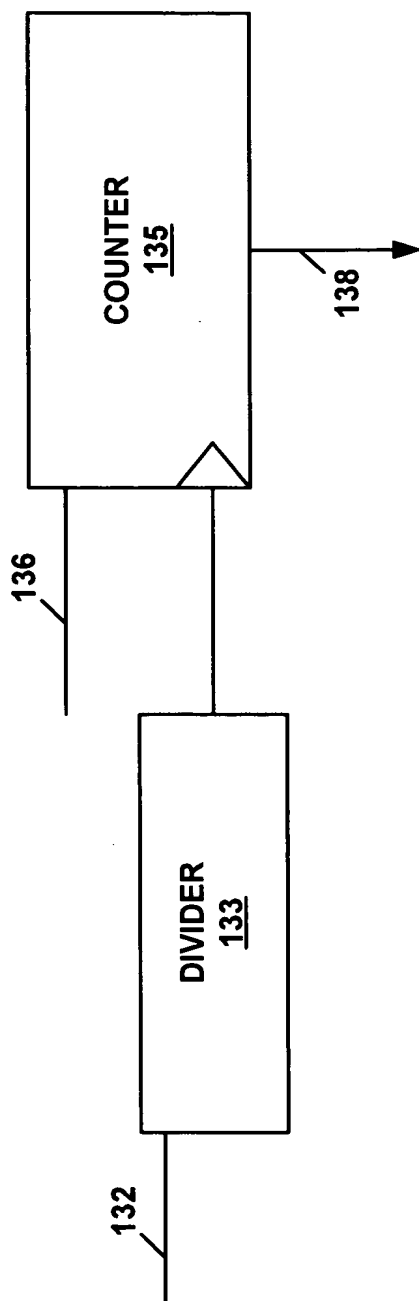


FIGURE 2

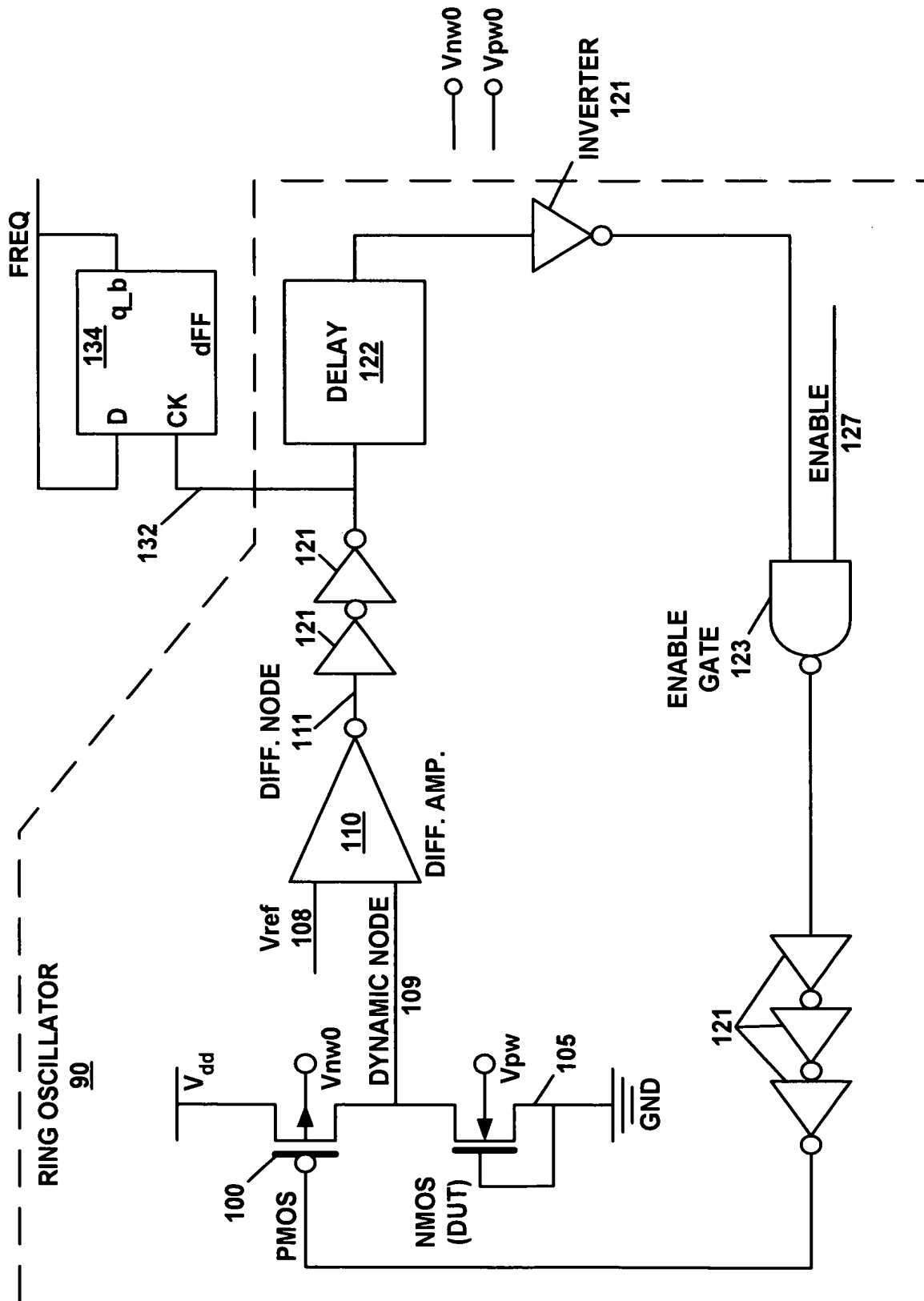
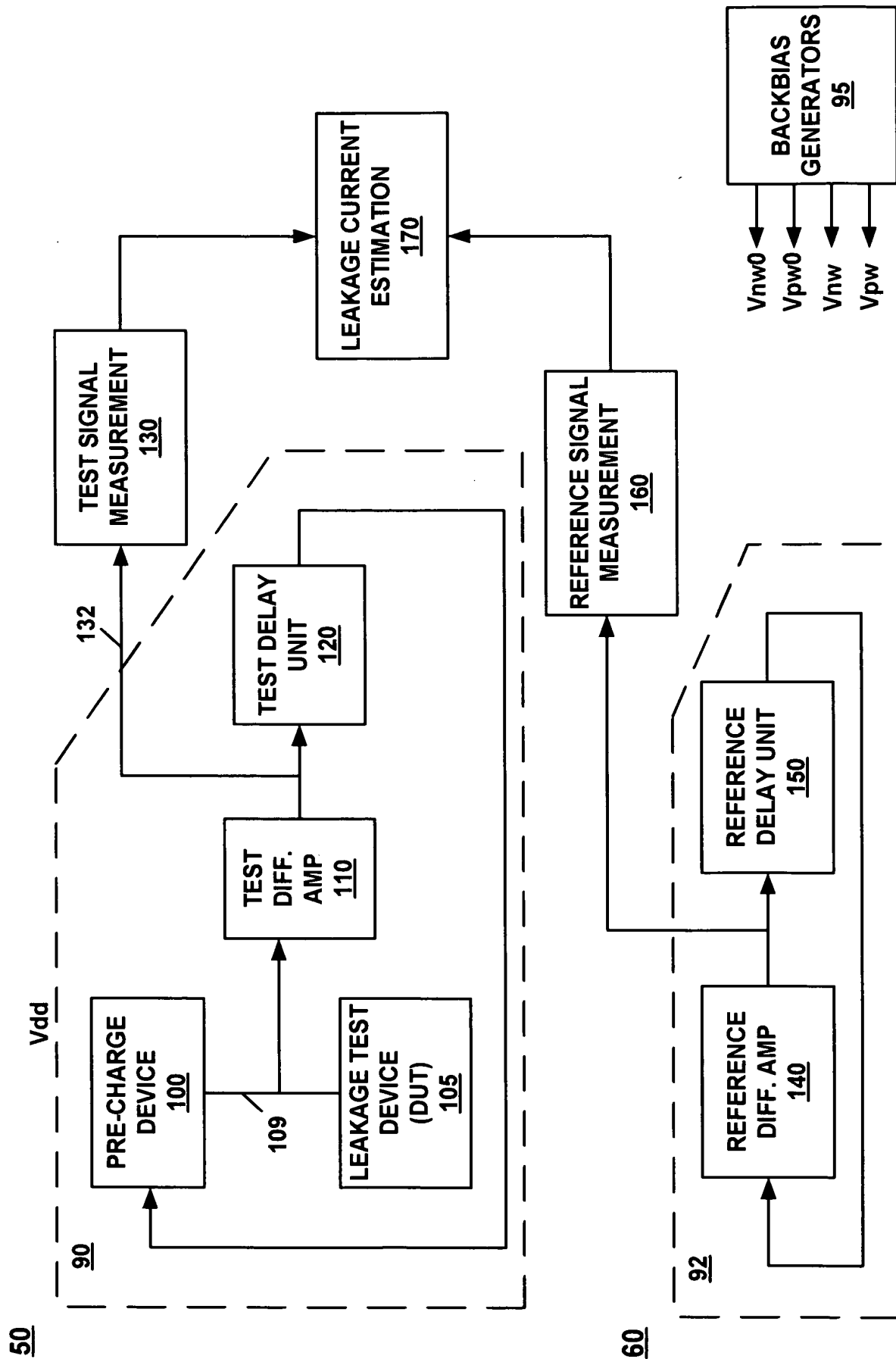


FIGURE 3





# FIGURE 5

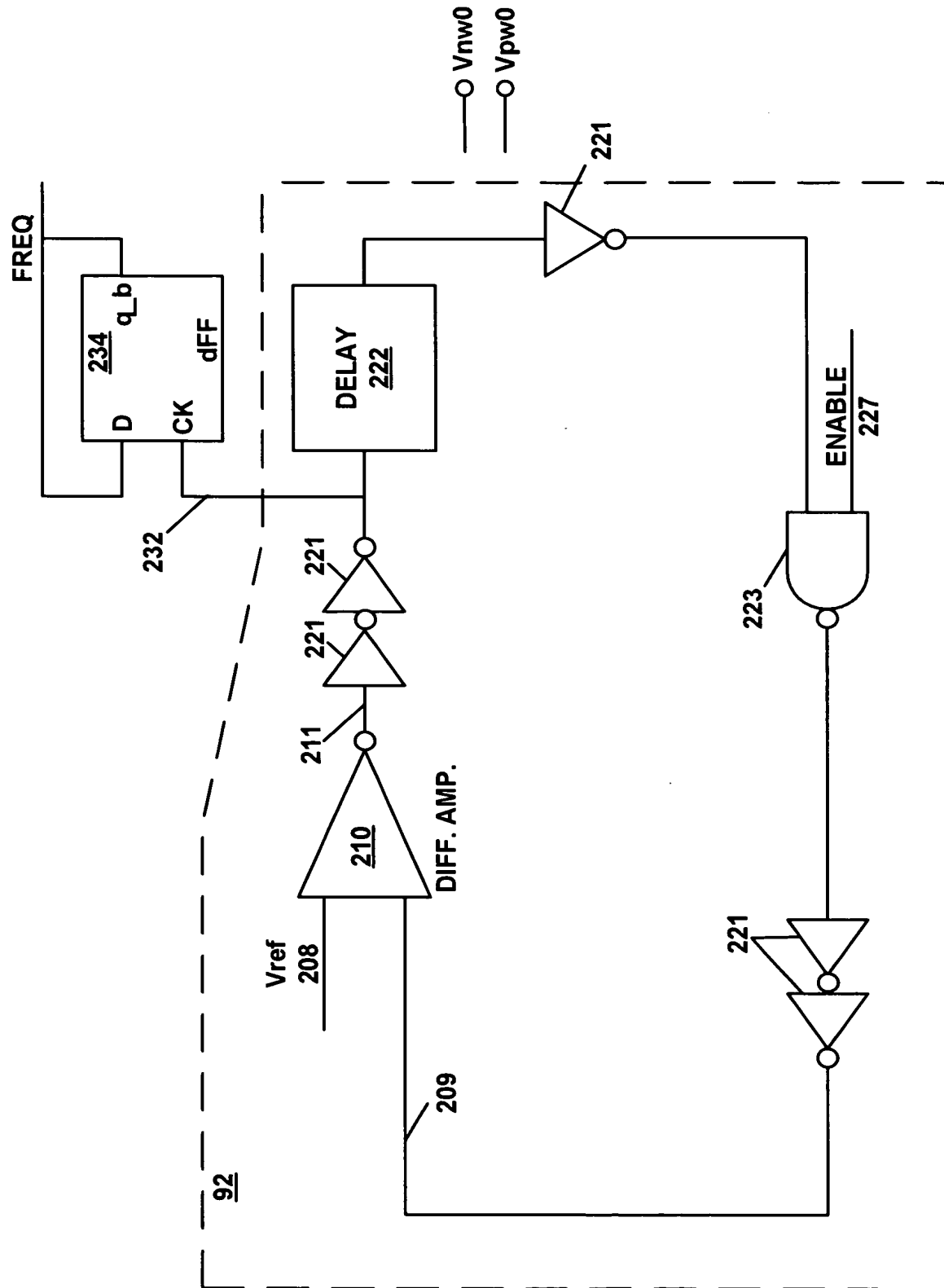


FIGURE 6

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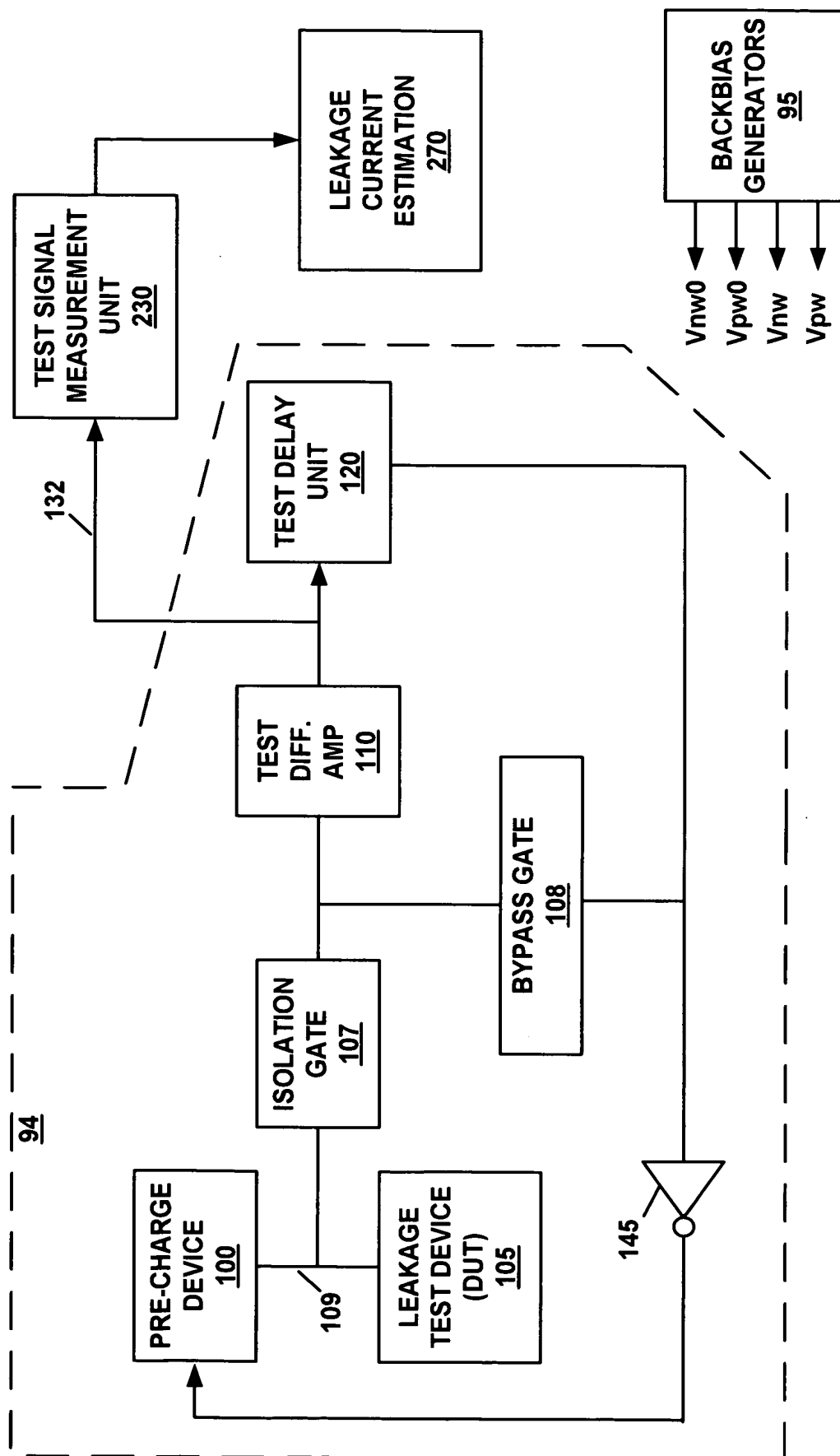
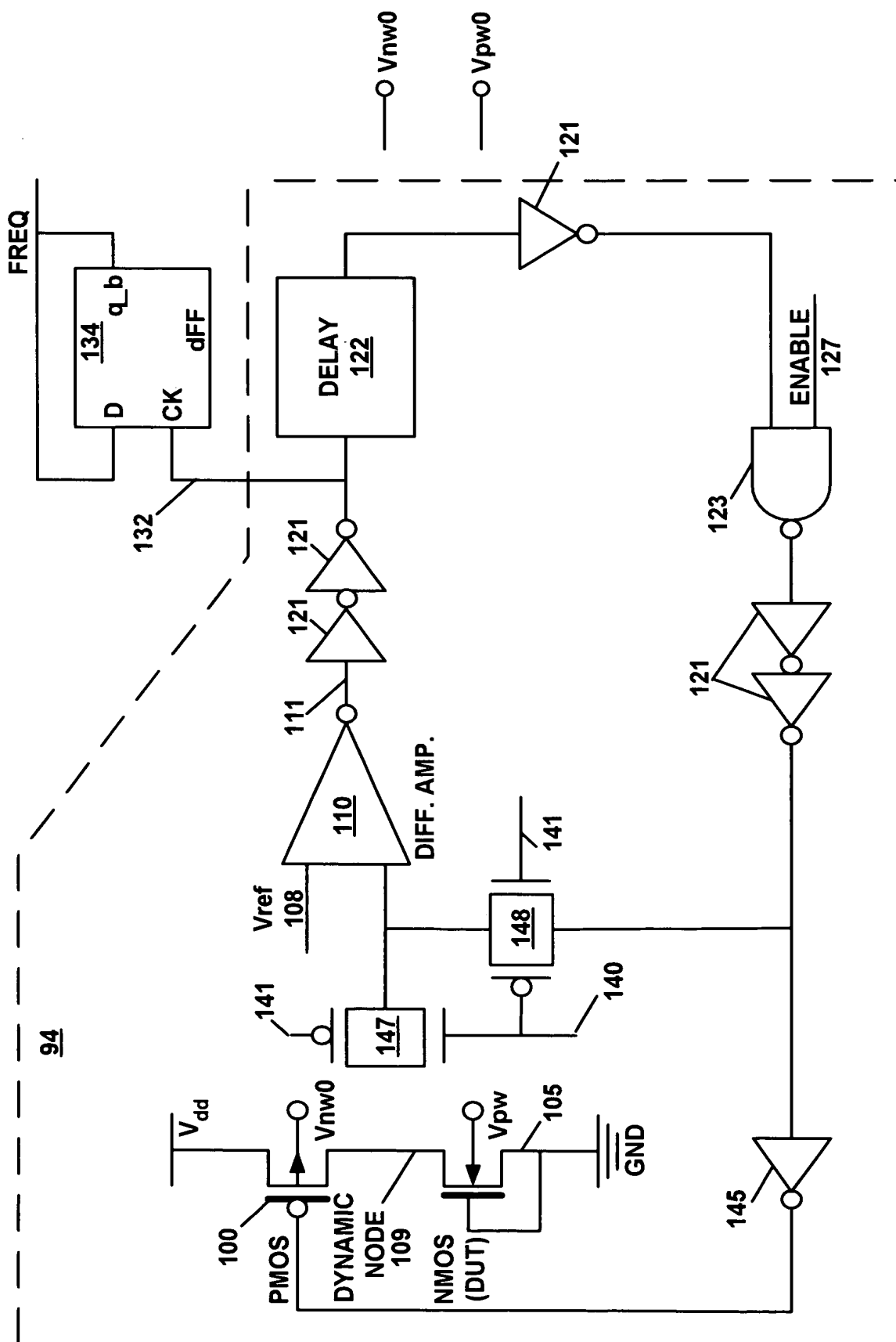
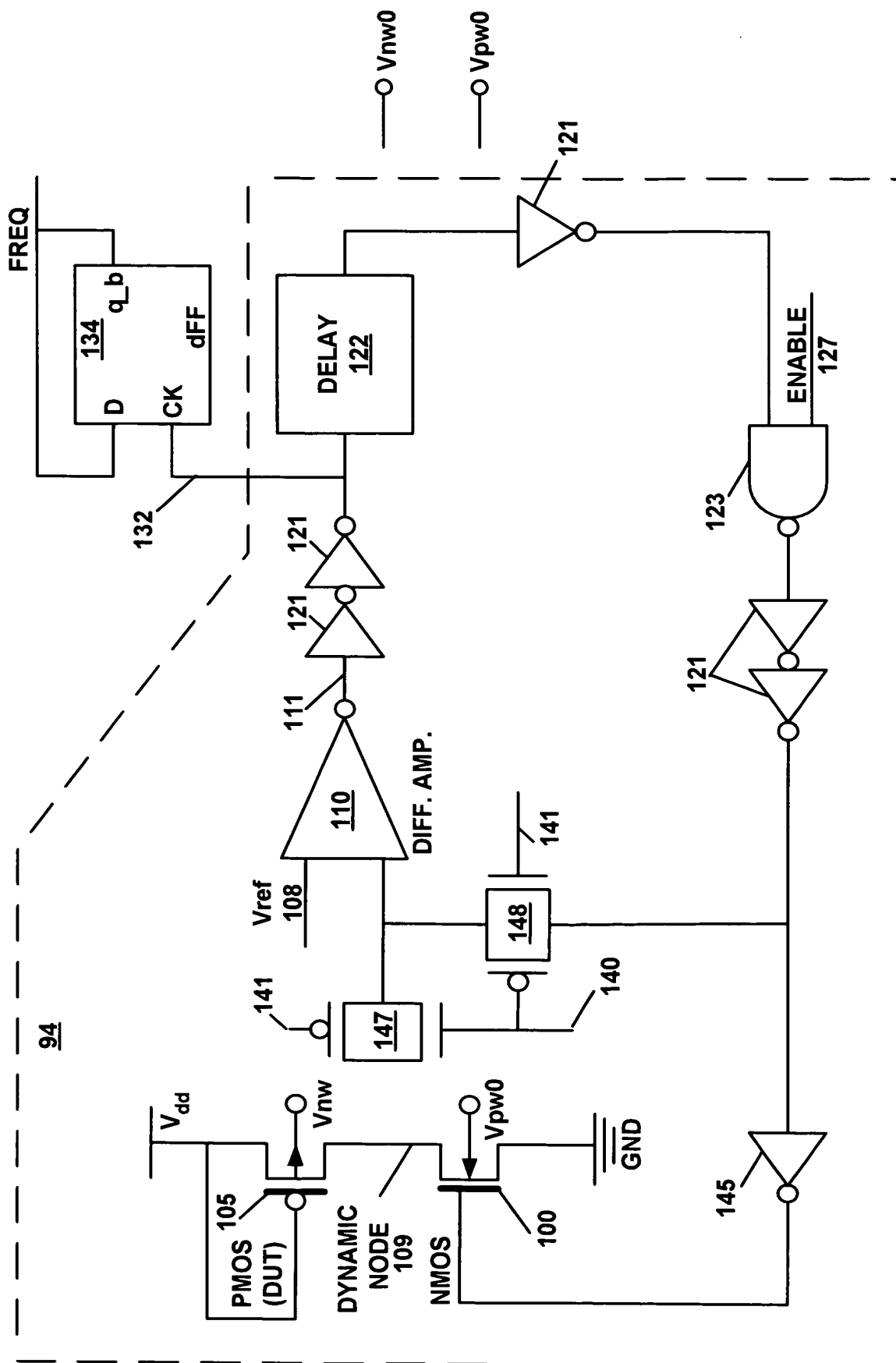


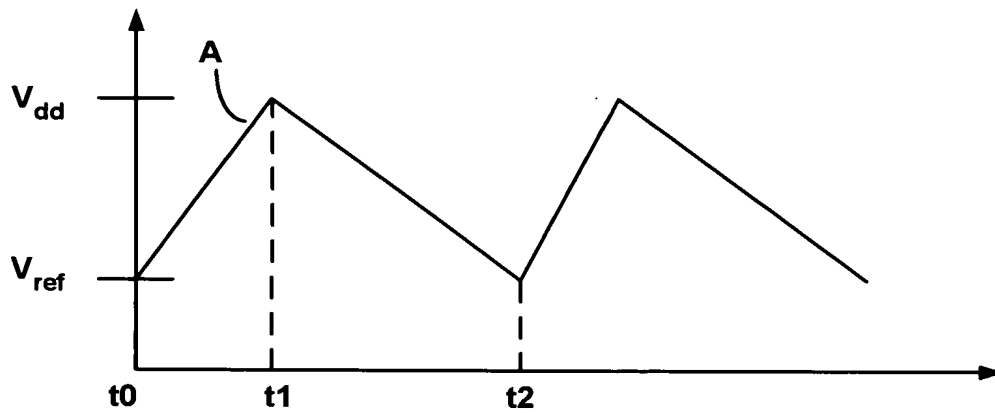
FIGURE 7



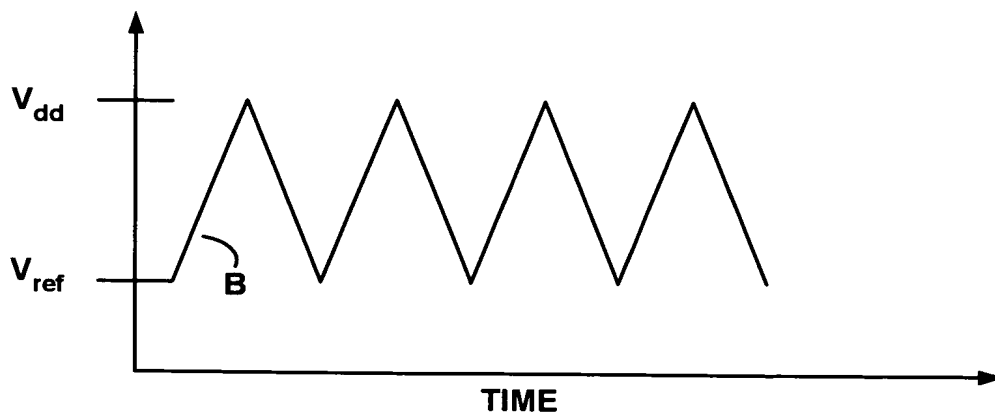




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**FIGURE 10A**



**FIGURE 10B**

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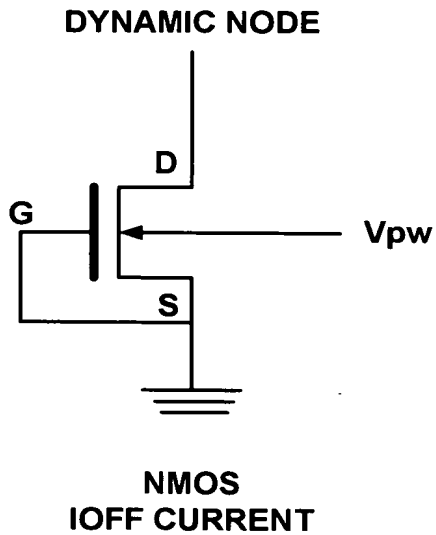


FIGURE 11

205

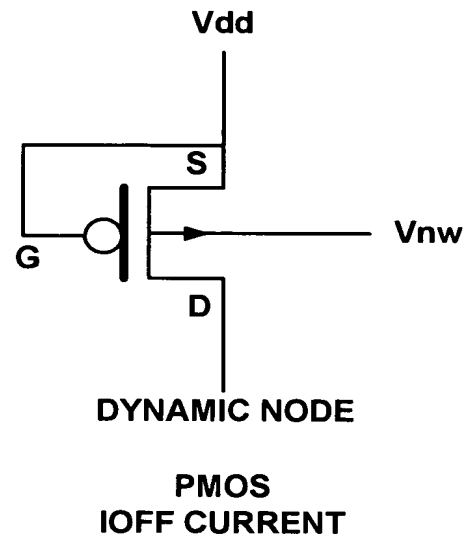


FIGURE 12

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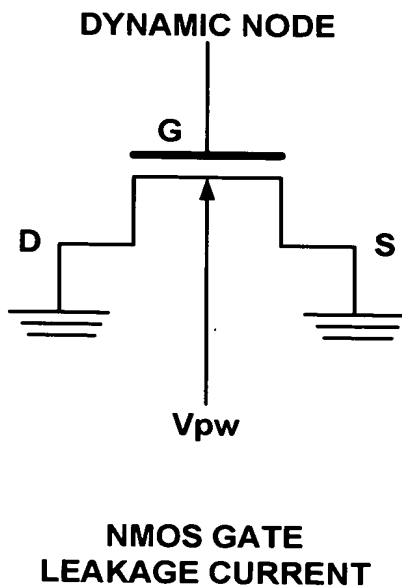


FIGURE 13

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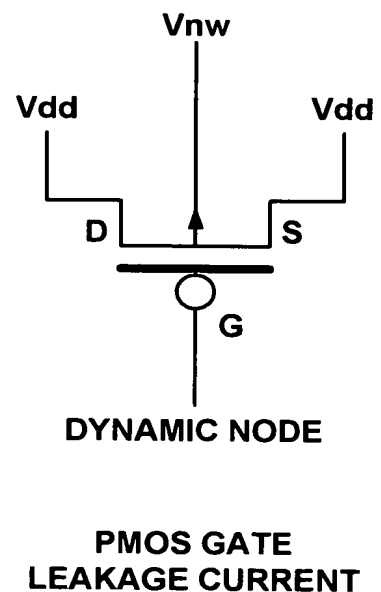


FIGURE 14

**ELECTRICAL CONNECTIONS:**

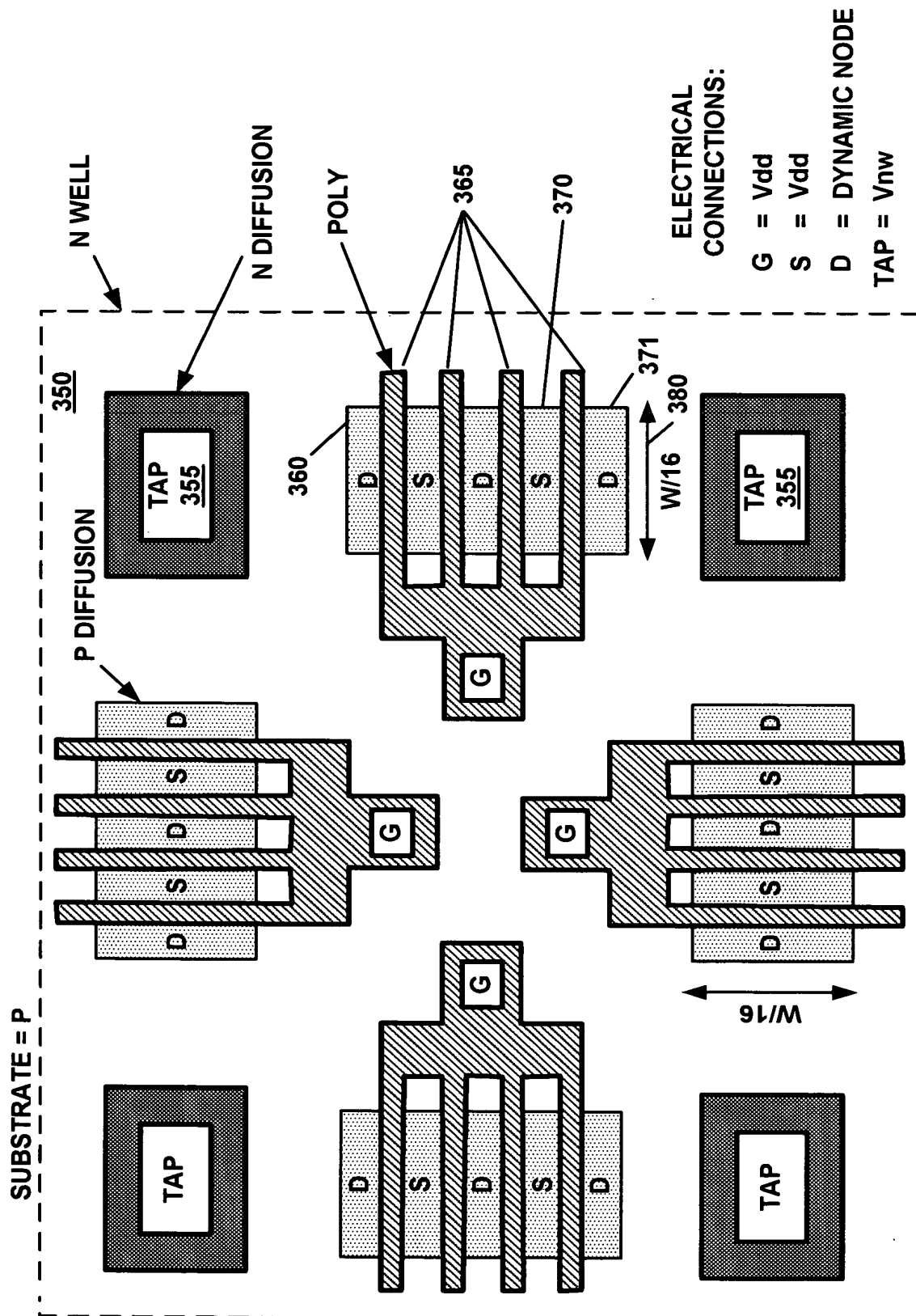
**G = GROUND**

**D = DYNAMIC NODE**

**S = GROUND**

**TAP =  $V_{pw}$**





# FIGURE 16

TITLE: SYSTEM AND METHOD FOR MEASURING TRANSISTOR LEAKAGE CURRENT WITH A RING  
OSCILLATOR WITH BACKBIAS CONTROLS

Inventor (s): Shingo Suzuki

Attorney Docket #: TRAN-P140.CIP

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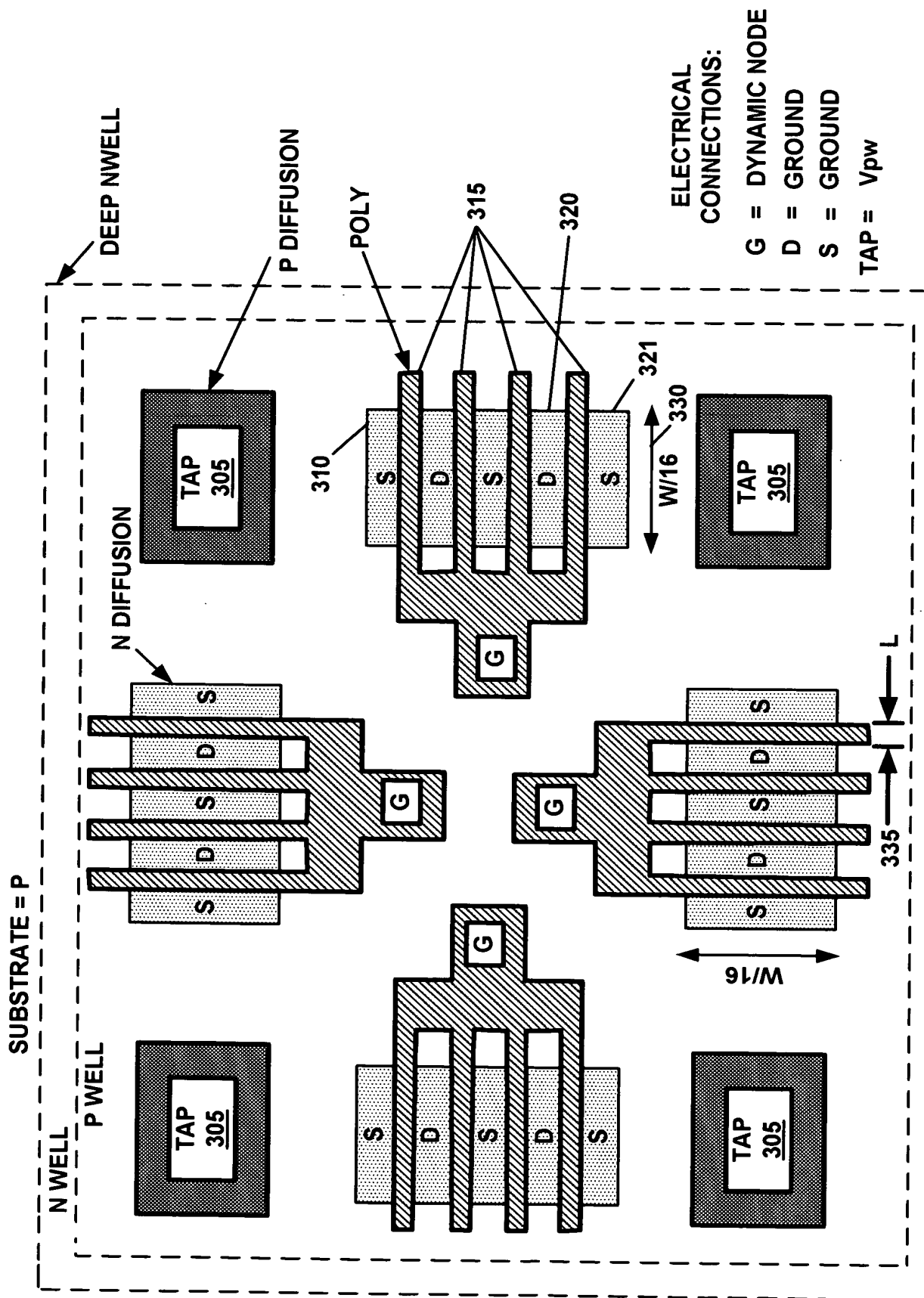
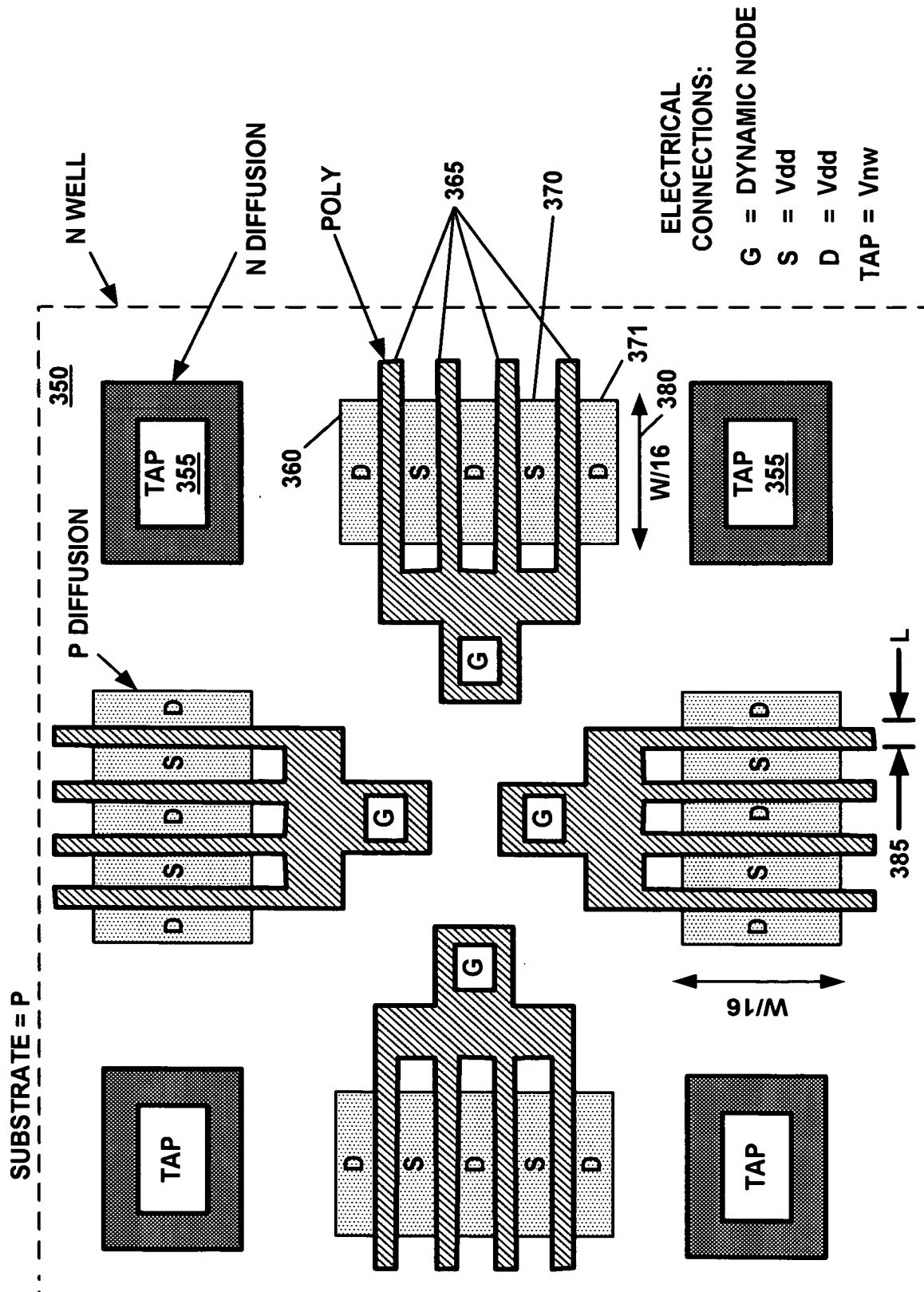


FIGURE 17



# FIGURE 18

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400

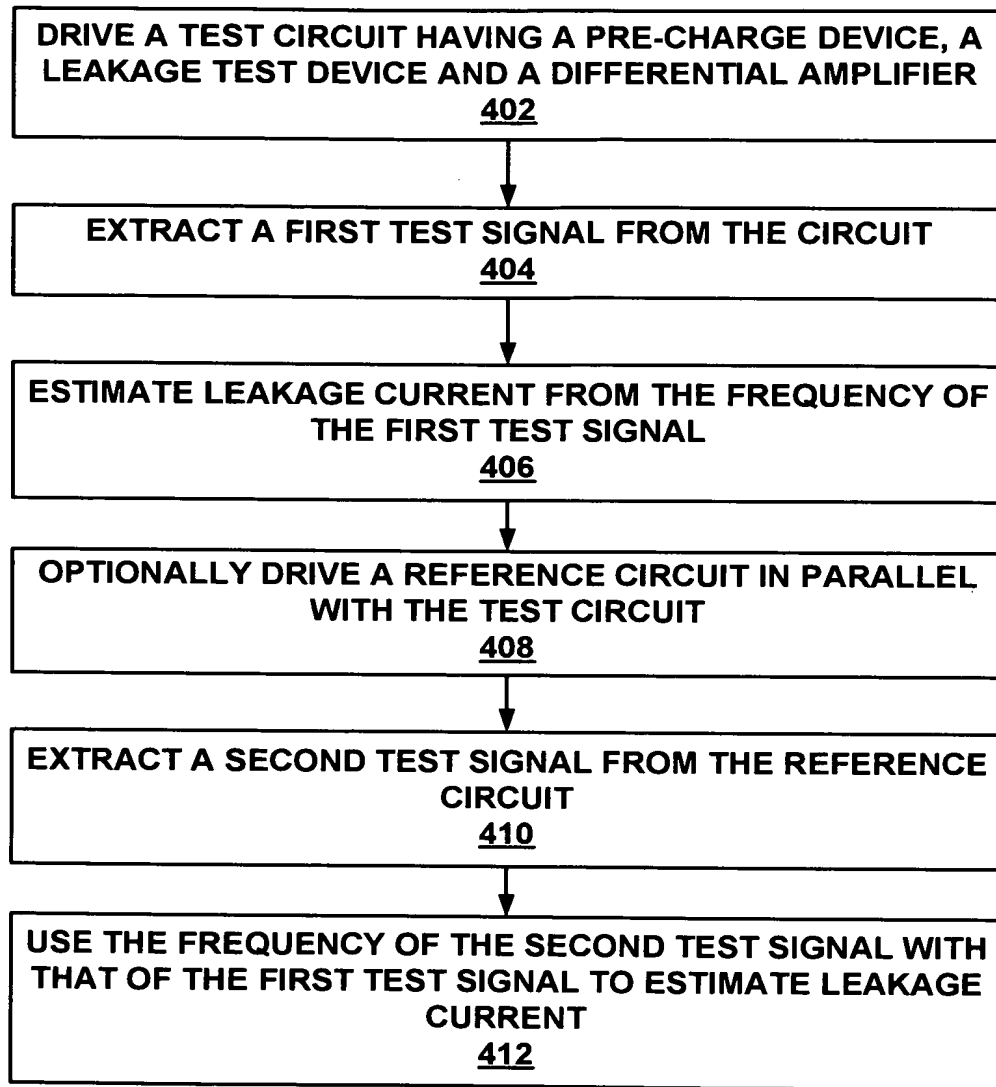


FIGURE 19